FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTORNEY DOCKET NO. 826.1767	APPLICATION NO. 09/985768
LIST OF REFERENCES CITED BY APPLICANT	FIRST NAMED INVENTOR Kwame Osei BOATENG	
(Use several sheets if necessary)	FILING DATE November 5, 2001	GROUP ART UNIT 2825

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
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FOREIGN PATENT DOCUMENTS

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OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

✓	AM	K. O. Boateng, H. Takahashi and Y. Takamatsu, "Diagnosing Delay Faults in Combinational Circuits Under the Ambiguous Delay Model," IEICE Transaction on Information and Systems, Vol. E82-D, No. 12, pp. 1563-1571.
✓	AN	K. O. Boateng, H. Takahashi, and Y. Takamatsu, "Multiple Gate Delay Fault Diagnosis Using Test-Pairs for Marginal Delays," IEIEC Transaction on Information and Systems, Vol. E81-D, No. 7, pp. 706-715.
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EXAMINER	MATHE SIBK	DATE CONSIDERED	6/14/05

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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTORNEY DOCKET NO. 826.1767	APPLICATION NO.
LIST OF REFERENCES CITED BY APPLICANT	FIRST NAMED INVENTOR Kwame Osei BOATENG	
(Use several sheets if necessary)	FILING DATE November 5, 2001	GROUP ART UNIT 2826

U.S. PATENT DOCUMENTS

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VS	AM	I. Pomeranz and S. M. Reddy, "On Test Compaction Objectives for Combinational and Sequential Circuits," Proceedings of IEEE International Conference on VLSI Design, pp. 279-284.
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EXAMINER	NUTHE SIEK	DATE CONSIDERED	6/14/05

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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTORNEY DOCKET NO. 826.1767	APPLICATION NO.
LIST OF REFERENCES CITED BY APPLICANT	FIRST NAMED INVENTOR Kwame Osei BOATENG	
(Use several sheets if necessary)	FILING DATE November 5, 2001	GROUP ART UNIT 1796

U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

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VS	AN	M. S. Hsiao and S. T. Chakradhar, "State Relaxation Based Subsequence Removal for Fast Static Compaction in Sequential Circuits," Proceedings of Design, Automation, and Test in Europe Conf., pp. 557-582.
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EXAMINER VUTHE SIEK	DATE CONSIDERED 6/14/05

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